


Substitute for form 1449A/PTO & 1449B/PTO			Complete if Known	
FIRST INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Application Number	10/743,815
			Filing Date	December 24, 2003
			First Named Inventor	Daniel Krähmer, et al.
			Examiner Name	Unassigned
			Attorney Docket Number	007413-071
Sheet	1	of	1	

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NON-PATENT LITERATURE DOCUMENTS	
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
D.R.	C. VAN PESKI, "Behavior of Fused Silica Under 193 nm Irradiation", International Sematech publication, Technology Transfer #00073974A-TR, July 25, 2000, International Sematech.
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Examiner Signature		Date Considered	6/9/05
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.